Photograph No.1 Setup for spurious emission field strength measurements below 30 MHz in the anechoic chamber



Photograph No.2
Setup for spurious emission field strength measurements from 30 MHz to 1000 MHz in the anechoic chamber



Photograph No.3
Setup for carrier, spurious emission field strength and occupied bandwidth measurements from 1 to 18 GHz in the anechoic chamber



Photograph No.4
Setup for field strength emission measurements at the OATS from 18 to 25 GHz

